

**Search Notes**

Application/Control No.

10/825,528

Examiner

Anthony Weier

Applicant(s)/Patent under  
Reexamination

SHEN ET AL.

Art Unit

1794

**SEARCHED**

Class	Subclass	Date	Examiner
updated	previous search	12/17/2007	AW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
426	656, 590		
	634, 598	12/17/2007	AW

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PGPubTextSearch	12/17/2007	AW